

# Optical absorption measurements in sapphire

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**Alexei Alexandrovski**

**Martin Fejer**

**Roger Route**

*Ginzton Laboratory, Stanford University*



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# Optical absorption measurements in sapphire

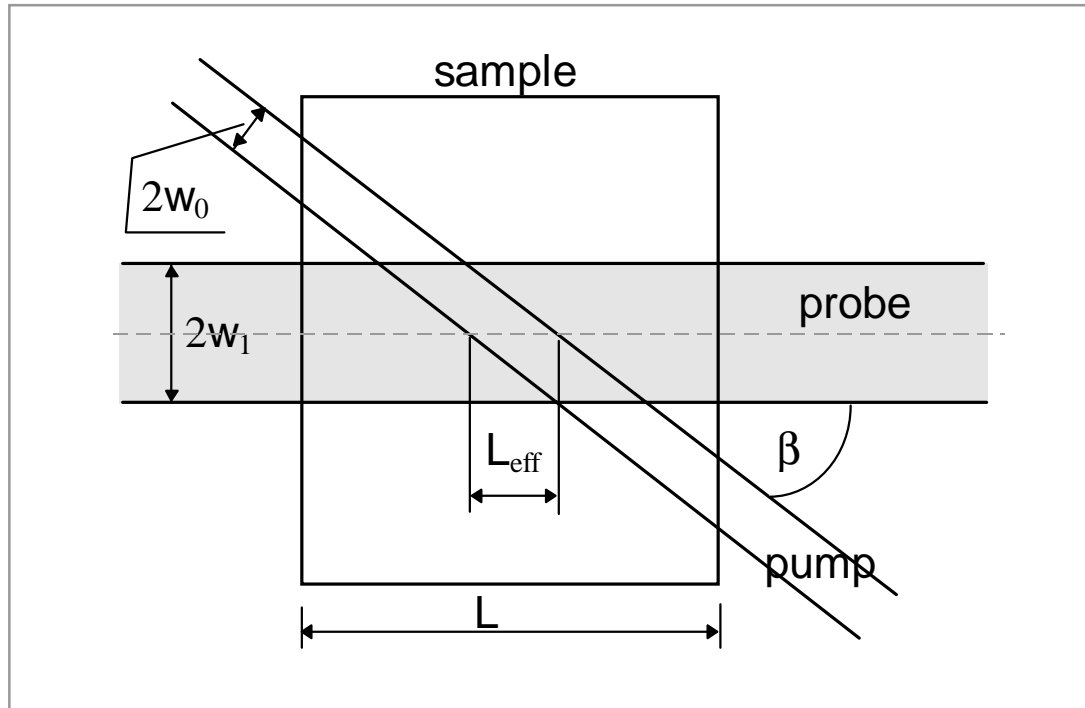
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## OUTLINE

- **Background**
- **Photothermal technique**
- **As-grown sapphire**
- **Annealed sapphire**
- **How to go below 40 ppm/cm**
- **Prospects**



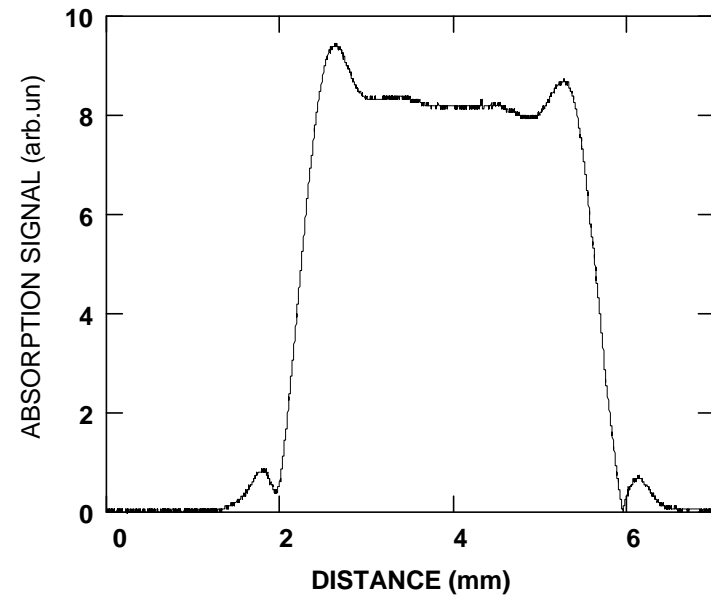
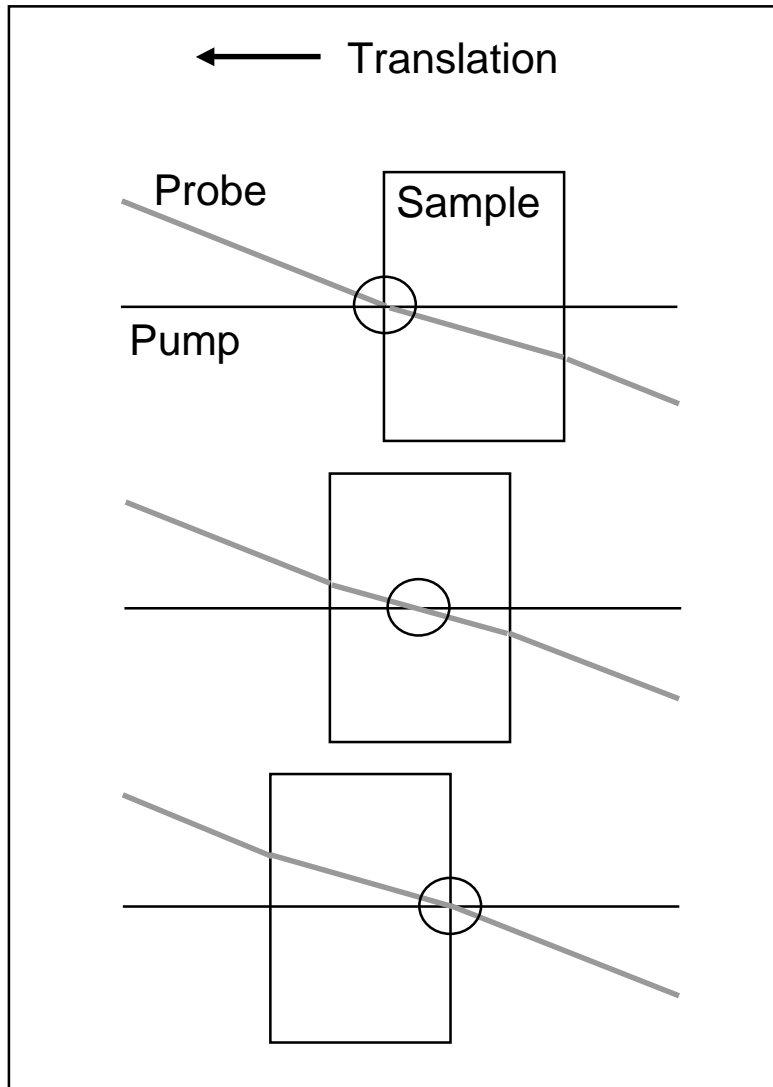
# Space resolution



$$L_{eff} = \sqrt{\frac{\pi}{2}} \frac{w_0}{\sin \beta}$$

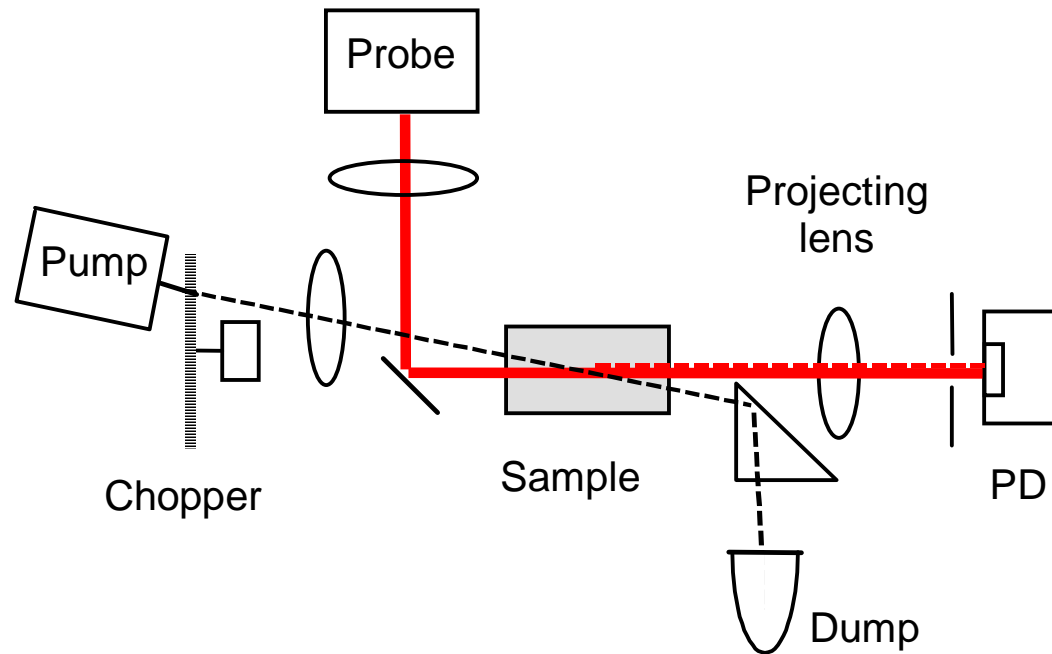
$$\alpha = \kappa \frac{P}{L_{eff}}$$

# Space resolution: surface-to-surface scan



**Example: 3 mm-thick neutral filter, 15%-absorbing**  
 **$L_{eff} = 0.25$  mm**

# Photothermal Common-path Interferometer (PCI)



Pump waist	50 $\mu$	Chopping frequency	380 Hz (10Hz - 2 kHz)
Probe waist	120 $\mu$	Crossing angle	1° - 20° (in air)
Pump power	5 W	Probe power	0.5 mW

- ac-component of probe distortion is detected by photodiode + lock-in
- absorption coefficient of  $10^{-7} \text{ cm}^{-1}$  can be detected with a 5 W pump
- **crossed beams** help to avoid false signals from optics and surfaces of the sample

## Data on sapphire crystals (1998)

Crystal	$\alpha$ (ppm/cm)		Scattering	Fluorescence
	532nm	1064nm		
'Window' 3mm-thick	1400*	81	No	$2 \times 10^{-3}$ F, Ti <sup>3+</sup>
CS 'White' #0	415* (bulk, anomaly near the surface)	41 (bulk, anomaly near the surface)	Large near the surface	$1 \times 10^{-3}$ F, Ti <sup>3+</sup> (bulk)
CS 'White' #1	1600	84	No	$3 \times 10^{-4}$ F
CS 'White' #2	1310	72	Weak band in the bulk	$1 \times 10^{-3}$ F
CS 'White' (Perth)	1910	129	Yes, broad band near one face	$3 \times 10^{-3}$ F
CS 'Hemex Ultra'	1150	188	No	$1 \times 10^{-4}$ F
0.1% Ti-doped (reference #2)	0.68/cm (total) 0.145/cm (thermal part)	6400	Yes, macro-defects	F, Ti <sup>3+</sup>
0.05% Ti-doped laser rod (reference #1)	-	19000**	-	0.7F, Ti <sup>3+</sup>

\* 514 nm

\*\* Absorption measured directly

Relative fluorescence brightness estimated with calibrated neutral filters,  
Ti-doped reference #2 brightness denoted as F

## Data on sapphire crystals (1999)

Crystal	$\alpha$ (ppm/cm)		Scattering	Fluorescence
	514nm	1064nm		
CS 'White', H <sub>2</sub> -annealed	605	53	No	$\approx 2 \times 10^{-4}$ F
CS 'White', O <sub>2</sub> -annealed	600 (bulk, anomaly near the surface)	47 (bulk, anomaly near the surface)	Large near the surface	$\approx 2 \times 10^{-4}$ F (bulk)
Substrate (TRW)	-	66	No	-
'Window' 3mm-thick	1400*	81	No	$2 \times 10^{-3}$ F, Ti <sup>3+</sup>
0.1% Ti-doped (reference #2)	0.68/cm (total) 0.145/cm (thermal part)	6400	Yes, macro-defects	F, Ti <sup>3+</sup>

Relative fluorescence brightness estimated with calibrated neutral filters, Ti-doped reference #2 brightness denoted as F

# Data on sapphire crystals (2000)

Crystal Systems, Inc.

Crystal	$\alpha$ (ppm/cm)		Scattering	Fluorescence
	514nm	1064nm		
1T	1730	124	No	$10 \times 10^{-5}$ F
1M	1800	103	No	$5 \times 10^{-5}$ F
1B	1430	91	No	$2.5 \times 10^{-5}$ F
2T	900	57	No	$4 \times 10^{-4}$ F
2M	900	87	No	$10 \times 10^{-4}$ F
2B	1410	92	No	$40 \times 10^{-4}$ F
3T	920	62	No	$10 \times 10^{-5}$ F
3M	1470	121	No	$5 \times 10^{-5}$ F
3B	840	66	No	$5 \times 10^{-5}$ F
4T	830	46	No	$10 \times 10^{-4}$ F
4M	1200	126	No	$2 \times 10^{-4}$ F
4B	1200	94	No	$1 \times 10^{-4}$ F

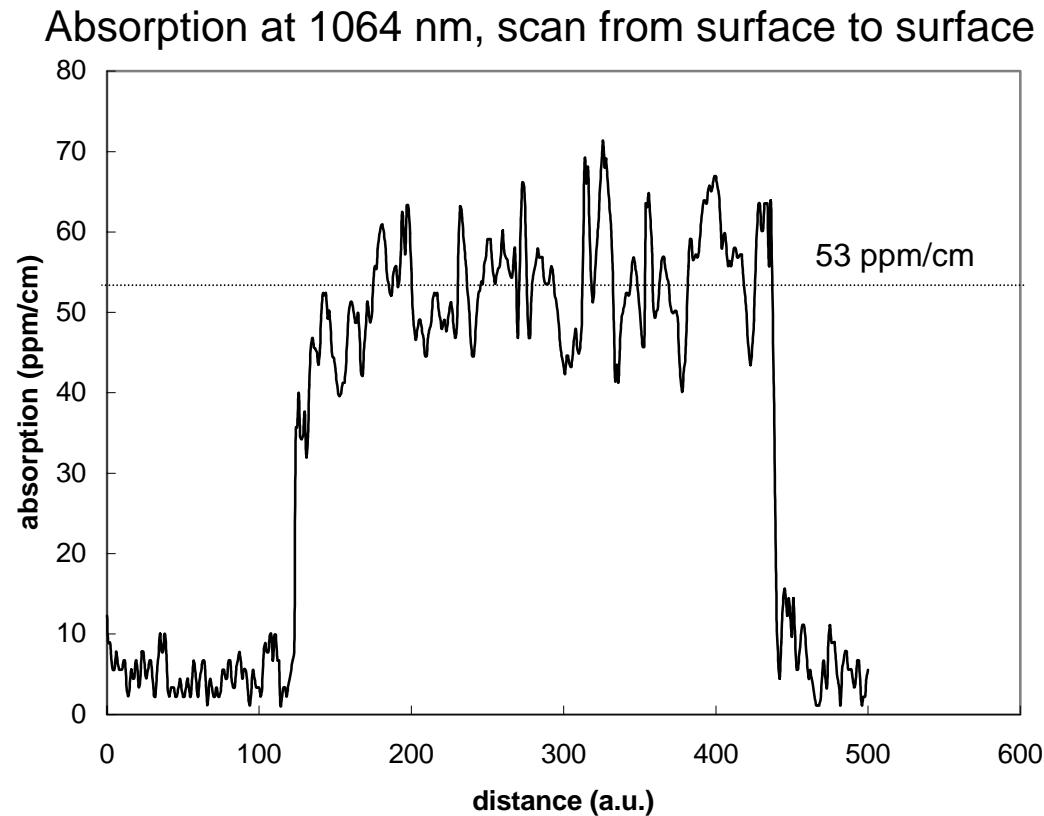
Nuclear Research Center – Negev, ISRAEL

Crystal	$\alpha$ (ppm/cm)		Scattering	Fluorescence
	514nm	1064nm		
1579	1570	147	No	$2 \times 10^{-3}$ F
1958	1600	140	No	$2 \times 10^{-3}$ F
1741	1560	211	No	$2 \times 10^{-3}$ F



# Annealed sapphire data

## 20 mm-long, H<sub>2</sub>-annealed sample

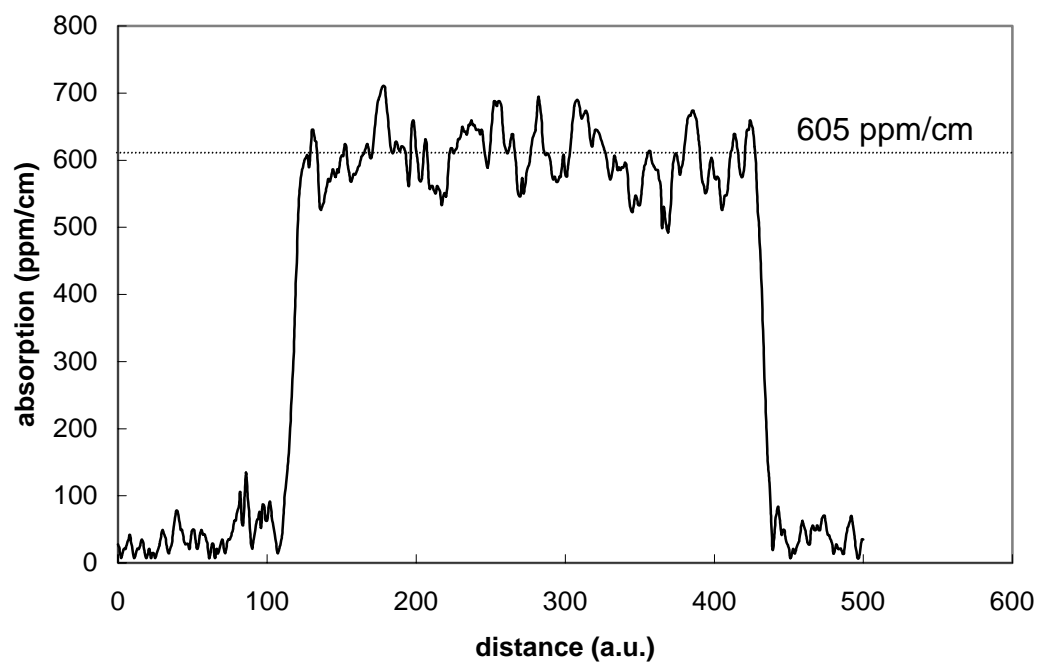


- Reference sample: Ti-doped sapphire with the absorption of 6400 ppm/cm at 1064 nm

# Annealed sapphire data

## 20 mm-long, H<sub>2</sub>-annealed sample

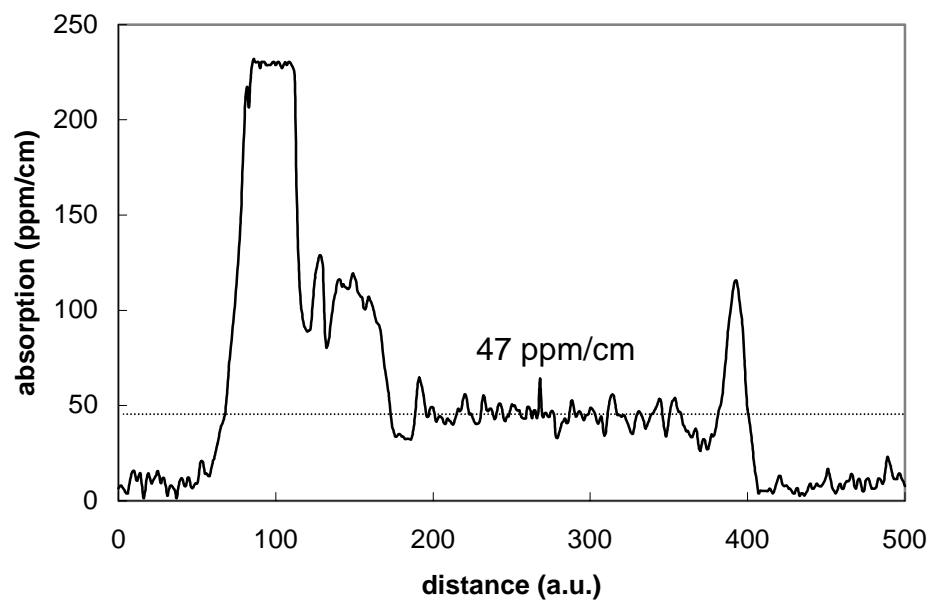
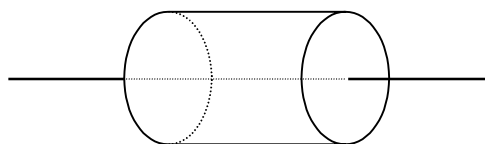
Absorption at 514 nm, scan from surface to surface



# Annealed sapphire data

## 20 mm-long, O<sub>2</sub>-annealed sample

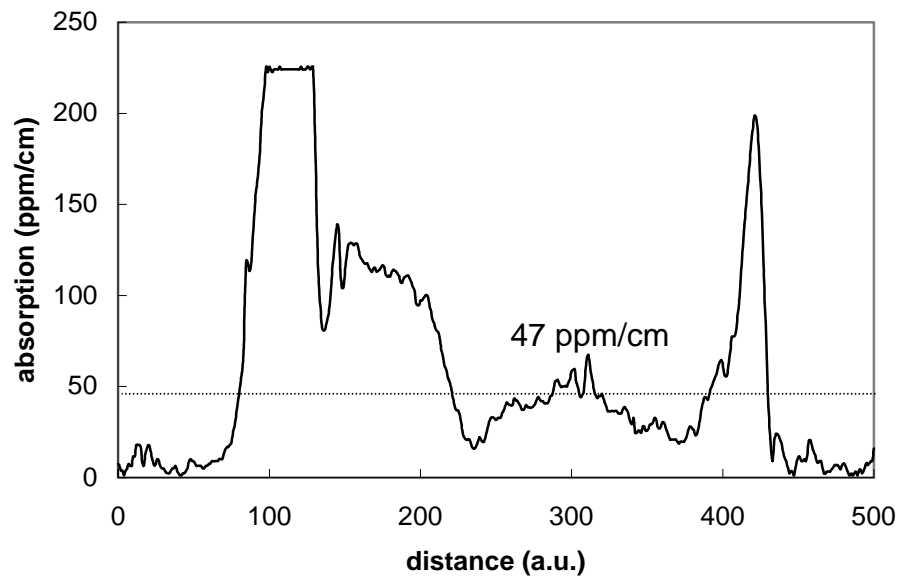
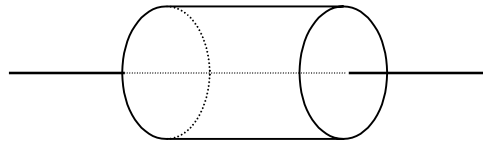
Absorption at 1064 nm, scan from surface to surface



# Annealed sapphire data

## 20 mm-long, O<sub>2</sub>-annealed sample

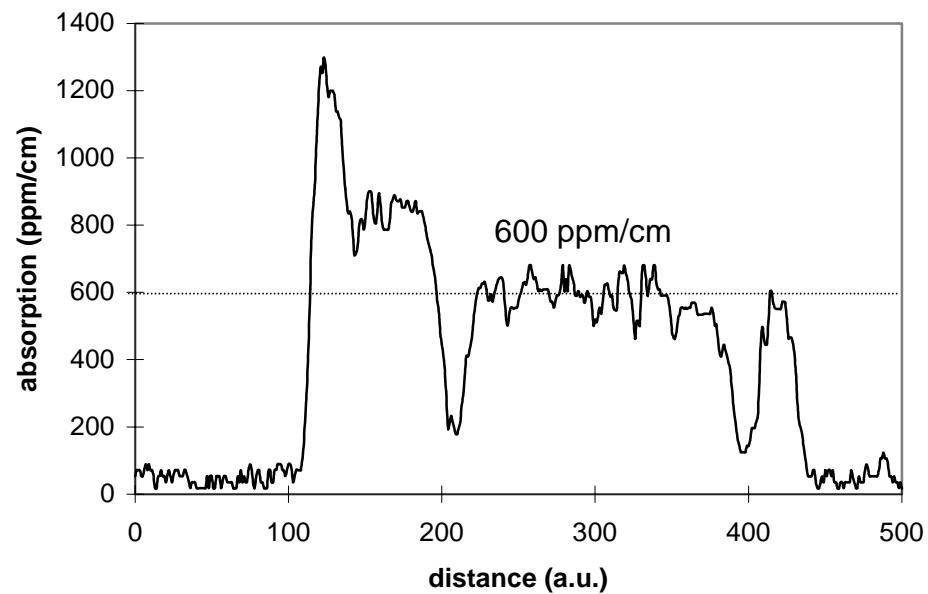
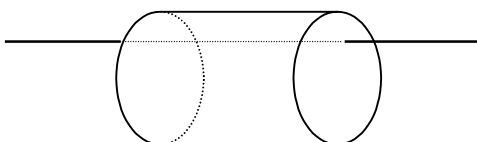
Absorption at 1064 nm, scan from surface to surface



# Annealed sapphire data

## 20 mm-long, O<sub>2</sub>-annealed sample

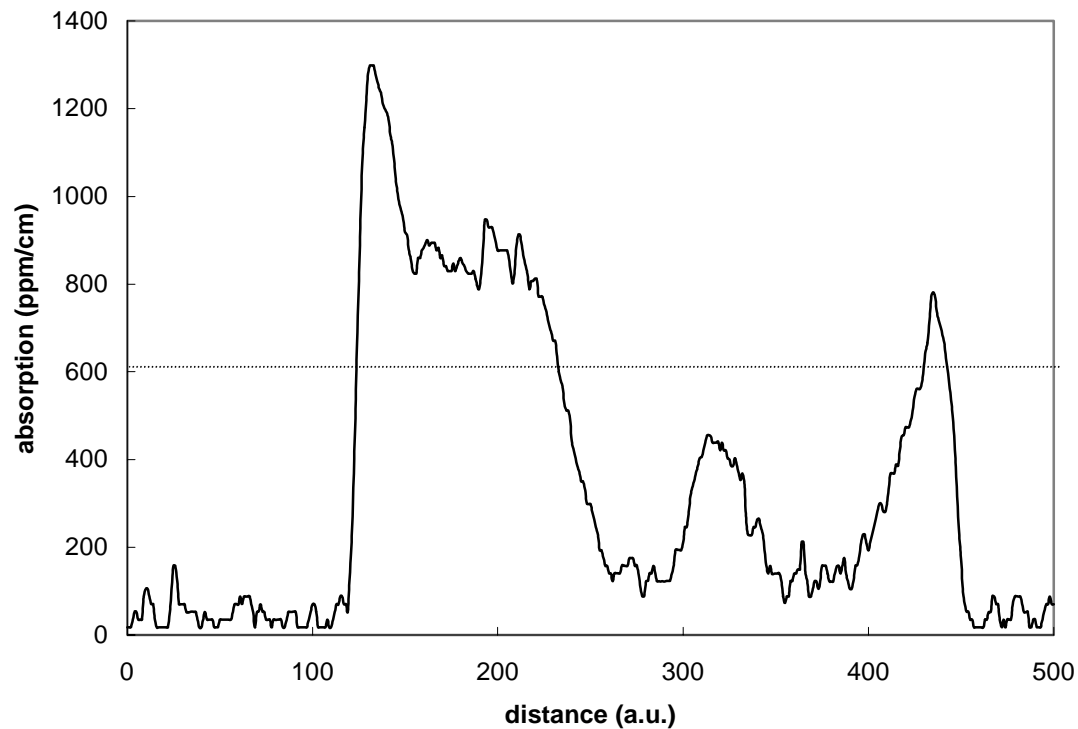
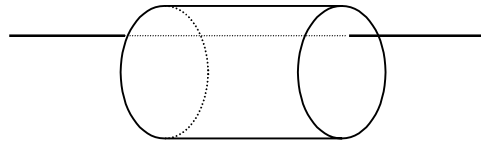
Absorption at 514 nm, scan from surface to surface



# Annealed sapphire data

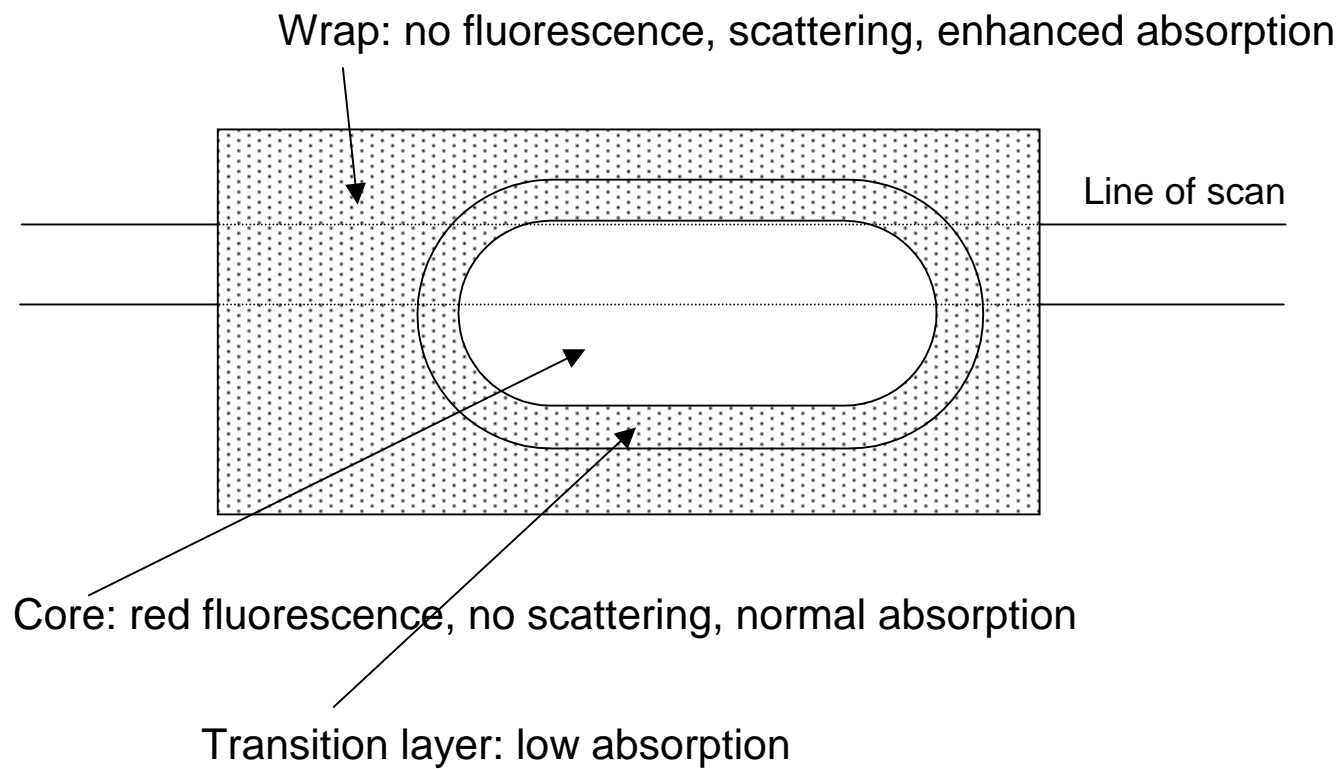
## 20 mm-long, O<sub>2</sub>-annealed sample

Absorption at 514 nm, scan from surface to surface



# Model

## O<sub>2</sub>-annealed sample



# Conclusions

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- ❖ The best as-grown sapphire shows 40 ppm/cm of absorption at 1064 nm
- ❖ H<sub>2</sub>-annealed sapphire shows no change in absorption, fluorescence or scattering
- ❖ O<sub>2</sub>-annealed sapphire shows a complex response to oxidation with local decrease of both IR and green absorption
- ❖ Defects responsible for current IR and green absorption levels are yet to be identified
- ❖ Proper annealing may offer means to reach the 10-15 ppm/cm level. Further decreases will depend on the ability to identify and eliminate specific defects

